

L Number	Hits	Search Text	DB	Time stamp
1	2	"6713351"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 12:03
2	2	"6636447"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 12:05
3	2	"6388283"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:47
4	14627	common adj terminal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:48
5	4640	trench\$2 adj capacitor\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:48
6	12	(common adj terminal) and (trench\$2 adj capacitor\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:49
7	3248	(trench\$2 adj capacitor\$1) and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:50
8	2558	different adj row	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:52
9	5	((trench\$2 adj capacitor\$1) and DRAM) and (different adj row)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:57
10	85230	DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 14:57
11	213	(common adj terminal) and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:01
12	20357	power adj converter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:01

13	189	((common adj terminal) and DRAM) and (not (power adj converter))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:11
14	31484	connecting adj line\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:12
15	33	(trench\$2 adj capacitor\$1) and (connecting adj line\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:12

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11	213	(common adj terminal) and DRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:01
12	20357	power adj converter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:01



Active

- L1: (2) "6713351"
- L2: (2) "6636447"
- L3: (2) "6388283"
- L4: (14627) common adj terminal
- L5: (4640) trench\$2 adj capacitor\$1
- L6: (12) 4 and 5
- L7: (3248) 5 and DRAM
- L8: (2558) different adj row
- L9: (5) 7 and 8
- L10: (85230) DRAM
- L11: (213) 4 and 10
- L12: (20357) power adj converter
- L13: (189) 11 and (not 12)
- L14: (31484) connecting adj line\$1
- L15: (33) 5 and 14
- L16: (3730) connecting adj region\$1
- L17: (26) 5 and 16

DB: USPAT; US PGPUB; EPD; IPO; DERWENT; IBM; IDS
Default operator: DR

5 and 16

7/20/04 TTN

	U	I	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Cla	Inventor	S	C	P	3	Image 1
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20040056248 AI	20040325	12	Test key for detecting electrical isolation between a word line and a d	257/48			Liu, Chih-Cheng et al	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2004
2	<input type="checkbox"/>	<input type="checkbox"/>	US 20030169629 AI	20030911	49	Semiconductor memory cell configuration and a method for produ	365/200	257/E21.652		Goebel, Bernd et al	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2003
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020187648 AI	20021212	85	Material removal method for forming a structure.	438/745	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2002
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020182872 AI	20021205	85	Material removal method for forming a structure.	438/705	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2002
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020182816 AI	20021205	83	Material removal method for forming a structure.	438/345	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2002
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020036310 AI	20020328	16	Trench capacitor having an insulation collar, and method of producing such	257/301			Lutzen, Jörn	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2002
7	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020001960 AI	20020103	89	Material removal method for forming a structure.	438/705	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 2002
8	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6756626 B2	20040629	15	Trench capacitor having an insulation collar	257/301	257/302		Lutzen, Jörn	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6756
9	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6599840 B2	20030729	82	Material removal method for forming a structure.	438/705	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6599
10	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6596648 B2	20030722	83	Material removal method for forming a structure.	438/745	257/E21.011; 257/E21.166		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6596
11	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6596642 B2	20030722	82	Material removal method for forming a structure.	438/705	216/38; 216/87;		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6596
12	<input type="checkbox"/>	<input type="checkbox"/>	US 6461967 B2	20021008	88	Material removal method for forming a structure.	438/705	216/38; 216/87;		Wu, Zhiqiang et al	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6461
13	<input type="checkbox"/>	<input type="checkbox"/>	US 6309975 B1	20011030	91	Methods of making implanted structures	438/705	216/38; 216/87;		Wu, Zhiqiang et al	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6309
14	<input type="checkbox"/>	<input type="checkbox"/>	US 6261964 B1	20010717	91	Material removal method for forminz	438/705	257/E21.011;		Wu, Zhiqiang et al	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 6261

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NUM

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15	33	(trench\$2 adj capacitor\$1) and (connecting adj line\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:43
16	3730	connecting adj region\$1	USPAT; US-PGPUB; EPO; JPO; . DERWENT; IBM_TDB	2004/07/20 15:44
17	26	(trench\$2 adj capacitor\$1) and (connecting adj region\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/07/20 15:44